PRODUCT CHANGE NOTICE

Wafer Fabrication Site Change for Intersil ISL59830IAZ* Products

Refer to:
PCN12076

Date: September 13, 2012

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September 13, 2012

To: Our Valued Intersil Customer

Subject: **Wafer Fabrication Site Change for Intersil ISL59830IAZ* Products –**
NXP Semiconductor Nijmegen, Netherlands

This notice is to inform you that Intersil has qualified the NXP Semiconductor facility in Nijmegen, Netherlands for wafer fabrication of the listed ISL59830IAZ* CQUBIC3 technology product. The change in wafer fabrication site is necessary as the NXP facility in Fishkill, New York has discontinued manufacturing operations. The CQUBIC3 technology wafer fabrication process has been relocated from the NXP Fishkill to the NXP Nijmegen facility. The product and technology qualification activities are complete.

Products affected: **ISL59830IAZ** **ISL59830IAZ-T13** **ISL59830IAZ-T7**

The NXP Nijmegen facility is ISO 9001:2008 and ISO/TS 16949:2002 certified. The product and technology qualification plans are designed using JEDEC and other applicable industry standards to confirm there is no impact to form, fit, function, or interchangeability of the product. A summary of the technology qualification results is included for reference. The remainder of the manufacturing operations (package assembly, package electrical testing, shipment, etc.) will continue to be processed to previously established conditions and systems.

There will be no change to the product data sheet specification or external marking of the packaged product. Product affected by this change is identifiable via Intersil's internal traceability system.

Intersil will take all necessary actions to conform to agreed upon customer requirements and to ensure the continued high quality and reliability of products being supplied. Customers may expect to receive product from either the current or the newly qualified sites beginning ninety days from the date of this notification or earlier with approval.

If you have concerns with this change notice, Intersil must hear from you promptly. Please contact the nearest Intersil Sales Office or call the Intersil Corporate line at 1-888-468-3774, in the United States, or 1-321-724-7143 outside of the United States.

Regards,

Jon Brewster

Jon Brewster
Intersil Corporation

PCN12076

CC: J. Touvell J. McNamara M. Carmody J. Bailey L. Tran H. Babcock C. Liu

PCN12076 –Technology Qualification Summary

Legend

Fail	Warning	Pass	QBE	Waived	NA

Reliability Test	EL8200IY NXP Nijmegen CQUBIC3 10 LEAD MSOP using SG600, CRM-1076DJ, 1 MIL GOLD wire at UNM	ISL59837IAZ NXP Nijmegen CQUBIC3 16 LEAD QSOP using SG600, A8290, 1 M GOLD wire at UNM
High Temperature Operating Life	SRN090285 Rev 0 0/99 125C 3000hr completed 2010-06-29 disposition=A SRN090285 Rev 1 0/78 125C 3000hr completed 2010-06-29 disposition=A SRN090285 Rev 5 0/78 125C 3000hr completed 2010-07-02 disposition=A	SRN100060 Rev 0 0/78 125C 3000hr completed 2010-10-05 disposition=A SRN100060 Rev 1 0/78 125C 3000hr completed 2010-10-05 disposition=A
Biased HAST	NA	SRN100060 Rev 0 0/77 130C, 85%RH PRECOND L2 PBFREE 96hr completed 2010-05-10 disposition=A SRN100060 Rev 1 0/50 130C, 85%RH PRECOND L2 PBFREE 96hr completed 2010-05-25 disposition=A
Storage Life	NA	SRN100060 Rev 1 0/78 150C BAKE AND REFLOW 1000hr completed 2010-07-20 disposition=A
Destructive Wire Pull after Storage Life	NA	SRN100060 Rev 0 0/4 completed 2010-02-08 disposition=C

PCN12076 –Technology Qualification Summary – cont.

Reliability Test	EL8200IY NXP Nijmegen CQUBIC3 10 LEAD MSOP using SG600, CRM-1076DJ, 1 MIL GOLD wire at UNM	ISL59837IAZ NXP Nijmegen CQUBIC3 16 LEAD QSOP using SG600, A8290, 1 M GOLD wire at UNM
Bond Pull Integrity	NA	SRN100060 Rev 0 0/3 175C 96hr completed 2010-05-05 disposition=A SRN100060 Rev 1 0/3 175C completed 2010-02-08 disposition=A SRN100060 Rev 2 0/3 175C completed 2010-02-08 disposition=A
Moisture Sensitivity Classification	MRT09118 MSL=2@260C (Pb Free) Approved=Yes	MRT10026 MSL=2@260C (Pb Free) Approved=Yes
Unbiased HAST	SRN090285 Rev 0 0/78 130C, 85%RH PRECOND L2 PBFREE 96hr completed 2009-12-09 disposition=A	NA
Temperature Cycle	SRN090285 Rev 0 0/78 -65C TO 150C PRECOND L2 PBFREE 500cy completed 2009-12-11 disposition=A	SRN100060 Rev 0 0/78 -40C TO 125C PRECOND L2 PBFREE 1000cy completed 2010-04-27 disposition=A
Destructive Wire Pull after Temp Cycle	NA	SRN100060 Rev 0 0/4 completed 2010-06-02 disposition=A
Product Electrical Characterization	Performed by Product Engineering	Performed by Product Engineering
ESD Characterization	Performed by Product Engineering HBM: 2500V MM: 400V CDM: 1000V	Performed by Product Engineering HBM: 2000V MM: 200V CDM: 1000V
Latch-up Characterization	Performed by Product Engineering Latch up Pass Class II Level A	Performed by Product Engineering Latch up Pass Class II Level A